

Form PTO 1449  
(Modified)DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
251241US2SERIAL NO.  
10/812,887

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT  
Katsufumi EHATAFILING DATE  
March 31, 2004

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>Jm</i>	AO	6-138076	05/20/1994	JAPAN		X
	AP			Reconsidered 2/30/06		
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV			none <i>Jm</i>		

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>Jm</i>	AW	Y. IJIMA, pages 20-23, "ELECTRONIC MONTHLY", 1998
<i>Jm</i>	AX	JIS R 1627, Japanese Standards Association, pages 1-18, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMICS AT MICROWAVE FREQUENCY", July 1996
<i>Jm</i>	AY	JIS R 1641, Japanese Standards Association, pages 1-29, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMIC PLATES AT MICROWAVE FREQUENCY", January 2002
	AZ	none

☐ Additional References sheet(s) attached

Examiner

*Jeff Hataleni*

Date Considered

8/19/05

\*Examiner: Initial reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.